Search Notes

Application/Control No.

10/813,011 Examiner

Hiep Nguyen

Applicant(s)/Patent under Reexamination

NOGUCHI, HIDEKAZU Art Unit

2816

SEARCHED					
Class	Subclass	Date	Examiner		

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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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